

Notice of References Cited	Application/Control No. 10/805,335		Applicant(s)/Patent Under Reexamination HAN ET AL.	
	Examiner Olivia T Luk		Art Unit 2812	Page 1 of 1

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	C	US-6,452,831	09-2002	Ahn et al.	365/148
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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